Notice of References Cited Application/Control No. 10/576,055 Examiner DAVID YI Applicant(s)/Patent Under Reexamination TANAKA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0081595	05-2003	Nomura et al.	370/353
*	В	US-2003/0187746	10-2003	Kochanski, Gregory P.	705/26
*	С	US-7,082,456	07-2006	Mani-Meitav et al.	709/203
*	D	US-2002/0065035	05-2002	Koshino, Masayuki	455/3.01
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.